Search	Notes
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Application/Control No.	Applica Reexar
10/635,647	сног
Examiner	Art Uni

German Colón

Applicant(s)/Patent under
Reexamination
CHOI ET AL.
Art Unit
2879

SEARCHED				
Class	Subclass	Date	Examiner	
updated	previous search	4/15/2005	GC	
313	309,336			
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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	Subclass	Subclass Date			

	DATE	EXMR
References from parent case were considered	4/15/2005	GC
text search in class 313; including tip, microtip and nanotube, nanofeatures		
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